

<b>Notice of References Cited</b>	Application/Control No. 10/579,238	Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
	Examiner SANG Y. PAIK	Art Unit 3742	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,282,227	08-2001	Schmitt et al.	372/107
*	B	US-7,088,761	08-2006	Iehisa, Nobuaki	372/101
	C	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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